

Annealing and Characterization of Irradiated Low Gain Avalanche Detectors

Tuesday 27 November 2018 12:00 (20 minutes)

Irradiated Low Gain Avalanche Detectors (LGADs) are investigated using the Transient Current Technique (TCT). The sensors are irradiated to a fluence of 10^{14} n_{eq}/cm². For different annealing times (at 60°C), the collected charge, the gain and the electric field profile is measured.

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